

Search Notes

Application/Control No.

10/526,686

Examiner

Son T. Nguyen

Applicant(s)/Patent under
Reexamination

CHARRIN ET AL.

Art Unit

3643

SEARCHED

Class	Subclass	Date	Examiner
47	41.01 41.11	9/26/2006	STN
	41.12 29.7		
	30 66.3		
	66.4 66.1		
	29.1 73		
220	4.21- 4.24		
428	34.1 34.2		
229	106 107		
	115 116		
	117.05		
206	423		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
IPC foreign search: A01G 7/00, 7/02, 7/04, 5/00, 9/02, 13/00, 13/02; A47G 7/00, 7/02, 7/04, 7/06, 7/07	9/26/2006	STN
consulted primaries Shian Luong, class 206 and Steve Castellano, class 220	9/25/2006	STN
text search, see printouts	9/26/2006	STN